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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270022
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clame	Dong Jang
APPROVED BY	APPROVED BY CUSTOMER:	
Please return one copy with approval to PSE-TW		

PSE Technology Corporation

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VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
Α	Jun.16,2016			Initial Release	
				_	

E0-R-4-014 Rev. E

G83270022

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ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270022

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 10	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements	
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm	
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ	
3	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.		
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.		
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.		

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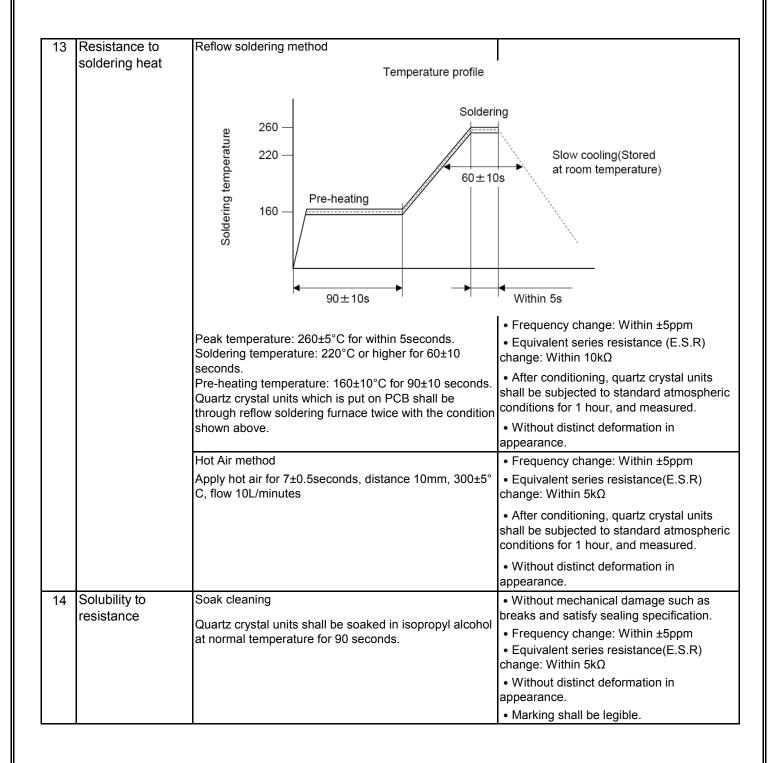
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6	Cold	Quartz crystal units shall b atmosphere for 1000 hours to JIS C 60068-2-1.	e stored in the -40±3°C s. Other procedures conform	 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall b atmosphere for 100 hours. JIS C 60068-2-2.		 After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat		e stored in the 40±2°C 6 relative humidity for 1000 onform to JIS C 60068-2-3.	
9	Change of temperature	Quartz crystal units shall b cycles of temperature char procedures conform to JIS		
		Temperatu 1 -40±3°C 2 Normal tempera 3 100±2°C 4 Normal tempera	30min. ature Within 30 sec. 30min.	
10 Sealing		Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes.		Without repetitive leaking bubbles from quartz crystal units. Av40.0 Do. m3/o or least
		Quartz crystal units shall b spectrometric leakage dete rate of helium gas.	e tested by Mass ector to measure the leakage	• 1×10-9 Pa·m3/s or less
11	Aging	Quartz crystal units shall b atmosphere for 720±12 ho		 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
12	Solder-ability Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds.		Minimum 95% of immersed terminal sha be covered with new uniform solder.	
		Items	Conditions	
		1 Solder	Sn-3.0Ag-0.5Cu	
		2 Flux	Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902).	

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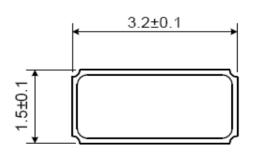
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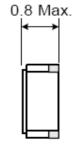
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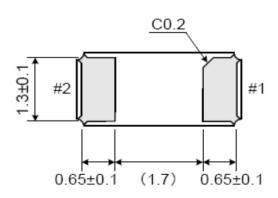
Marking



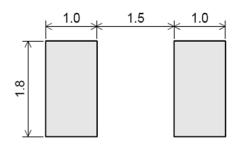
Dimensions (Units: mm)



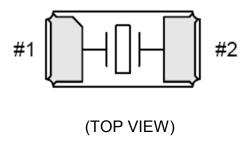




Recommended Soldering Pattern



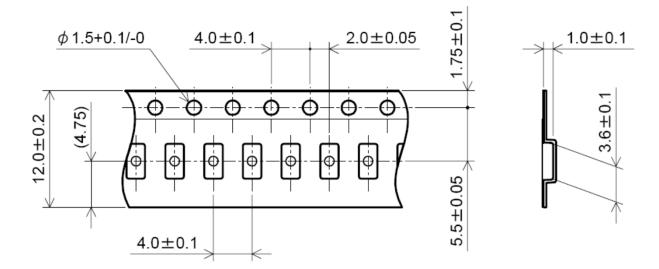
Internal connection



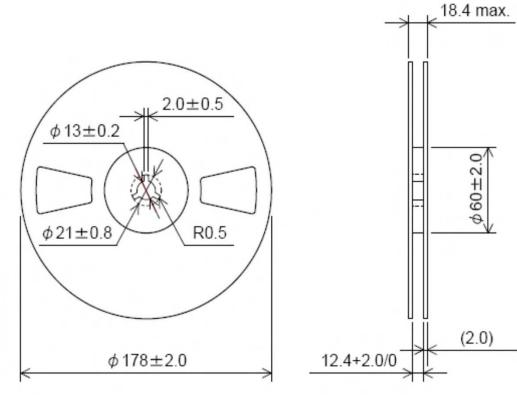
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TAPING (Units: mm)



REEL (Units: mm)



Quantity: 3000pcs / Reel

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